NEW AND/OR INTERESTING IN MICROSCOPY

A reminder to mark your calendars:

Microbeam Analysis Society (MAS) National Meeting (Breckenridge, CO) - August 6/11 '95.

Microscopy Society of America (MSA) & Histochemical Society Annual Meeting (Kansas City, MO) - August 13/17 '95.

The XIVth International Pfefferkorn Conference of the Science of Biological Specimen Preparation for Microscopy and Microanalysis will be held on August 6-11, 1995 in Belleville, IL. This conference aims at creating a platform for discussion of the preparation of cells and biomolecules for imaging in vivo and in vitro. Specimen preparation techniques (for the following microscopy methods: fluorescence; differential-interference; real-time confocal laser scanning; infrared; atomic force and scanning tunneling; conventional, high resolution and field emission scanning electron; etc.) to be discussed include: whole mounts, immunolabelling, in situ hybridization, cryo-immobilization, freeze-fracture, freeze-drying, freeze substitution, low temperature embedding, extractable embeddments, thin film deposition, positive and negative staining, conductive staining, cryo-untramicrotomy, etc. For further information, contact Dr. Ohm Johari at tel.: 708)529-6677, fax: 708)980-6698.

The National Center for Electron Microscopy is offering a fellowship that will allow participants the opportunity to conduct research in their own area of interest using the advanced transmission electroscopes at the Center.

The program is intended primarily for young faculty/investigator electron microscopists, resident in the U.S. who are in the process of setting up their own facilities or are awaiting delivery of new equipment, and who could benefit from the head-start that use of instrumentation and interaction with personnel at NCEM would bring. However, other post-doctoral applicants with suitable experience and graduate students would also be considered.

Fellowships will be of up to three-months duration and will carry a stipend of up to $6,000 to assist in defraying travel and living expenses. Applications must be received by April 7, 1995. For further information, contact Gretchen Hermes: tel.: (510)486-5006, fax: (510)486-5888, eMail: ghermes@lbl.gov

Published bi-monthly, ultra*structural pathology*, is the only journal to be devoted entirely to diagnostic ultrastructural pathology. It contains original research papers and concise reviews by leading authorities in the field. For a free sample copy, contact Taylor & Francis, Inc., 1900 Frost Road, Ste. 101, Bristol PA. 19007. Tel.: (800)821-8321, Fax: (215)785-5515.

NEW PRODUCT NEWS

Leica is proud to introduce **LEO (Leica Electron Optics) software** for the LEICA S400 Series of SEMs. Through customer feedback and a policy of continuous improvement, the development of the Leica **LEO** software reflects the changing needs of Leica SEM users.

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ELECTRON MICROSCOPY SCIENCES is proud to announce the upcoming release of their 1995 product catalog covering a complete line of chemicals, supplies, and equipment for all fields of MICROSCOPY AND HISTOLOGY. For a free copy, please call or write today to:

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Circle Reader Inquiry # 28

Diatome, the leading manufacturer of diamond knives and accessories has the answer to all of your microscopy and microtomy needs. Whether you deal in biological or material sciences, in E.M. or L.E., at ambient or low temperatures, Diatome makes a knife for you. With three standard knife angles (35°, 45°, 55° - others available upon request) and six different types of knives (ultra thin, seim thin, cryo wet, cryo dry, histo and histo cryo), Diatome covers the entire microscophy spectrum. For more information on any of our diamond knives and accessories, please call or write us today:

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Circle Reader Inquiry # 29

Many thanks to Lucille Giannuzzi (Univ. of Central Florida) for the use of her set of microscopy-related cartoons in this newsletter.

And a special thanks to Thierry Epicier (Institute National des Sciences Appliquees de Lyon) for the cartoons used in this issue.

We invite others to provide "light" material (cartoons, quotes, etc.). In addition to using them in the newsletter, we intend to publish them all in a set and send to all interested parties.

Don Grimes, Editor

COMING EVENTS

✓ March 5/10 '95: **PITTCON '95.** New Orleans, LA. (412)825-3220, Fax: (412)825-3224.

✓ March 20/24 & 27/31 '95: **Practical Aspects of Scanning Electron Microscopy.** Univ. of MD Short Course. College Park, MD. Tim Maugel, Tel.: (301)405-6898, Fax: (301)314-9358.

✓ March 21/24 '95: **Digital Microscopy** March 28/31 '95: **EELS Imaging & Analysis** (Gatan). Pleasanton, CA. Chris Byrne: (510)463-0200

✓ March 28/31 '95: **SCANNING '95.** Monterey, CA. Mary K. Sullivan: (201)818-1010, Fax: (201)818-0086.

✓ April 4/7 '95: **Ultramicrotomy in Materials Science.** RMC. Tucson, AZ. Bob Chiovetti: Tel.: (602)889-7900, Fax: (602)741-2200.

✓ April 4/7 '95: **Expoanalitica + Biociencia** Madrid, Spain. Tel.: +343 423 31 01, Fax: +343 423 63 48.

✓ April 6/7 '95: **FT-IR Microscopy Training Course.** (Spectra-Tech, Inc.). Shelton, CT. Debbie Esposito: Tel.: (800)243-9186, (203)926-8998 (CT)

✓ April 17/21 '95: **Spring MRS Meeting.** San Francisco, CA. Mary Kaufold: (412)367-3036.

✓ April 18 '95: **Light Element EDS Workshop** Univ. of Minnesota, Nolte Ctr., Minneapolis, MN Gib Ahlstrand: Tel.: (612)625-8249, eMail: giba@ puccini.crl.umn.edu

✓ April 18/20 '95: **Focus On Microscopy 95.** Taipei, Taiwan. P.C. Cheng: (716)645-3868.

✓ April 24/29 '95: **22nd International Conference on Metallurgical Coatings and Thin Films** (AVS). San Diego, CA. Mary Gray. Tel.: (301)870-8756, Fax: (301)645-1426.

✓ May 6/11 '95: **Food Structure Annual Meeting** (Scanning Microscopy International). Houston, TX. Dr. Om Jahari. Tel.: (708)529-6677. Fax: (708)980-6698.

✓ May 15/17 '95: **TEM Specimen Preparation** (Gatan). Pleasanton, CA. Chris Byrne: (510)463-0200.

✓ May 16/18 '95: **Computer-Assisted Image Analysis and Measurement** (North Carolina State Univ.). Raleigh, NC. Belinda Niedwick: Tel.: (919)515-2261, Fax: (919)515-7614.

✓ May 20/24 '95: **EUCHEM Conference on Electron Microscopy in Solid State Science.** Lund, Sweden. Swedish Nat'l Committee for Chemistry. Tel: +46-(0)8-4115280

✓ May 29/June 23 '95: **Introduction to the Meiofauna** (Univ of S. Carolina short course). Gerogetown, SC. Kitty Harper. (803)777-2692

✓ June 4/7 '95: **22nd Annual Meeting of the Microscopical Society of Canada.** Univ of Ottawa. Shea Miller, Tel.: (613)957-4347 X-7709, Fax: (613)943-2353.

✓ June 6/9 '95: **3rd Annual Symposium on AFM & STM** (US Army Natick RD&E Ctr. Natick, MA. Samuel Cohen: (508)651-4578

✓ June 7/9 '95: **Confocal Microscopy and Quantitative Image Analysis** (Geo. Washington Univ. 21st Annual Program). Washington, DC. Fred G. Lightfoot (202)994-2881, Fax: (202)994-8885.

✓ June 12/22 '95: **Lehigh Microscopy Courses - SEM, X-ray Analysis, AEM, AFM.** Bethelem, PA. Prof. David B. Williams, Tel.: (610)758-5133, Fax: (610)758-4244.

✓ June 15/17 '95: **Microwave Workshop.** (Ted Pella, Inc.) California State Univ, Chico, CA. Rick Giberson: Tel.: (800)237-3526 (US) or (800)637-3526 CA), Fax: (916)243-3761.

New RMS Microscopy Handbook

PhotoMACROgraphy

Brian Bracegirdle

Cold Aston Lodge, Cold Aston, Cheltenham, Glos. UK

A detailed practical guide to the choice of equipment and methods for both transmitted-light and reflected-light photography. Recommended for all who wish to record photographic images at moderate magnifications, whether relative novices or more experienced workers.

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105 pages, 52 photographs, tables and illustrations.

Price: $30.00 U.S. Plus $4.00 S&H

Available from *Microscopy Today* by check, Visa/MasterCard or company purchase order. Address, etc. on page 3.